



International Conference on Electrical, Computer and Communication Engineering (ECCE 2025)



Certificate of Contribution

Md Rifat Hossen, and Md Nahian Abdullah

Paper ID: 821

Paper Title: Advancing Semiconductor Fabrication: A CNN-Based Wafer Defect Detection with XAI Insights

Accepted and Presented in
4th ECCE held on 13-15 February 2025 at CUET, Bangladesh.

Prof. Dr. Md. Rubaiyat Tanvir Hossain
Technical Chair

Prof. Dr. Mohammad Shamsul Arefin
Organizing Chair



Organized By

Faculty of Electrical and Computer Engineering (ECE)
Chittagong University of Engineering & Technology (CUET)
Chattogram-4349, Bangladesh